

Test Socket

- High performance test socket with various solutions
- Various design solutions for manual and ATE handler operation
- Quick turn design capability and custom design solutions
- Cost effective and fast lead time thru in-house manufacturing

I Design Features

- Standard/custom design for ATE handler
- Manual test application with manual lid
- Standard/custom footprint
- Dual operation on both ATE and manual
- User friendly designs

I Test Solutions

- Design solution for any type of package types
- Various applications Production, Development, Engineering, Characterization
- Adaptable to most of existing load boards
- Long operation cycles under ATE handler operation
- Cost effective

I Product Category

Devices

Digital, Analog, Imaging, Microcontroller, ASIC, EEPROM, Flash, Mixed Signal, Wireless, RF, CMOS image sensor, LED

Packages

-Lead package: M/TQFP, T/SOP, D/QFN, CLCC, etc

-Ball package: BGA, CSP, WLP, etc



I Product Line-up

		BGA/CSP	QFN/MLF	TQFP	TS0P	WLCSP
Pitch (MIN) Contact		0.3mm	0.2mm	0.4mm	0.4mm	0.25mm
		Spring probes,	Spring probes,	Spring probes,	Spring probes,	Spring probes
		Genaro pin	Genaro pin	Genaro pin	Stamped pin	Genaro pin
Design	Clamshell					•
	Bottle cap, Open top					
	Other designs					